

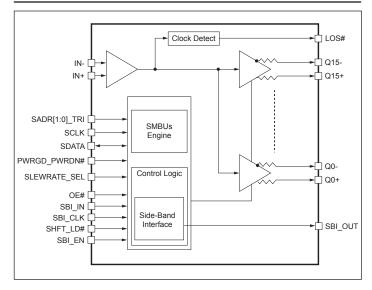


#### 16-Output Low-Power Fanout Clock Buffer for PCIe 6.0 Application

### Description

The PI6CB332016A is a low-power PCIe® 5.0/6.0 clock buffer. It takes a reference input to fanout 16 low-power differential HCSL outputs up to 400MHz, with on-chip terminations for  $85\Omega$  output impedance. An individual OE pin for each output provides easier power management. The device also supports Power Down Tolerant (PDT), automatic output clock parking upon loss of input clock, and Flexible Startup Sequencing features.

### **Block Diagram**



#### **Features**

- 16 Low-Power HCSL Outputs with On-Chip Termination
- $85\Omega$  Output Impedance •
- ٠ Individual Output Enable
- Supports I/O Power Down Tolerant
- Flexible Startup Power Sequencing ٠
- Automatic Output Clock Parking Upon Loss of Input Clock
- Up to 9 Selectable SMBus Addresses •
- Supports SBI OE# Interface
- Differential Output-to-Output Skew <50ps
- Additive Phase Jitter
  - PCIe 5.0: Typical 5fs RMS
- PCIe 6.0: Typical 3fs RMS
- DB2000QL: Typical 10fs RMS
- 3.3V Supply Voltage
- Temperature Range: -40°C to 105°C
- Packaging (Pb-free & Green):
- 64-Pin, TQFN 9mm x 9mm (ZD)
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- For automotive applications requiring specific change control (i.e. parts qualified to AEC-Q100/101/104/200, PPAP capable, and manufactured in IATF 16949 certified facilities), please contact us or your local Diodes representative. https://www.diodes.com/quality/product-definitions/

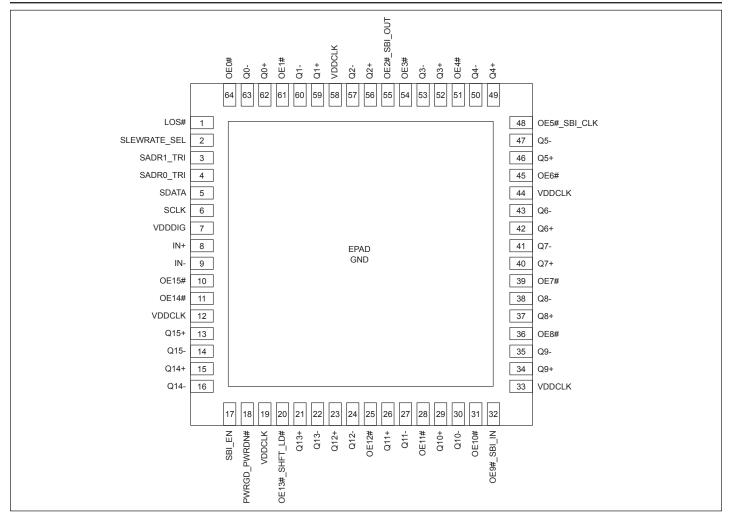
#### Notes:

- No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant. 1.
- See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free. 2.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.





### **Pin Configuration**



### **Pin Description**

Pin Number	Pin Name	Ту	pe	Description	
1	LOS#	Output	Open Drain	Open drain output, needs external pull up, Low output indicates loss of input clock signal, PDT.	
2	SLEWRATE_SEL	Input	CMOS	Input to select default slew rate of the outputs. 0 = Slow Slew Rate, Fast Slew Rate. Internal pull up.	
3	SADR1_tri	Input	Tri-level	SMBus address bit. This is a tri-level input that works in conjunction with SADR0_TRI pin, to decode SMBus addresses. It has internal pull-up/down resistors to bias to VDD/2. See the SMBus Address Selection table.	
4	SADR0_tri	Input	Tri-level	SMBus address bit. This is a tri-level input that works in conjunction with SADR1_TRI pin, to decode SMBus addresses. It has internal pull-up/down resistors to bias to VDD/2. See the SMBus Address Selection table.	





Pin Number	Pin Name	Ту	pe	Description
5	SDATA	I/O	CMOS	Data pin for SMBus interface.
6	SCLK	Input	CMOS	Clock pin of SMBus interface.
7	VDDDIG	Power		Digital power.
8	IN+	Input	Diff.	True clock input. PDT. Internal pull down.
9	IN-	Input	Diff.	Complementary clock input. Internal pull up.
10	OE15#	Input	CMOS	Active low input for enabling output 15. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
11	OE14#	Input	CMOS	Active low input for enabling output 14. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
12	VDDCLK	Power		Clock power supply.
13	Q15+	Output	Diff.	True clock output.
14	Q15-	Output	Diff.	Complementary clock output.
15	Q14+	Output	Diff.	True clock output.
16	Q14-	Output	Diff.	Complementary clock output.
17	SBI_EN	Input	CMOS	0 = SBI is disabled. $1 = SBI$ is enabled.
1/	SDI_EN	Input	CMOS	Internal pull down, PDT.
18	PWRGD_PWRDN#	Input	CMOS	1 = power good mode, I2C address is latched. 0= power down mode.
				Internal pull up, PDT.
19	VDDCLK	Power		Clock power supply.
				$SBI_EN = 0: OE mode$
		_		0 = Enable output 13, 1 = Disable output 13
20	OE13#_SHFT_LD#	Input	CMOS	SBI_EN = 1: SBI mode
				This pin becomes SHFT_LD pin.
21	012	Output	Diff.	For both OE mode and SBI mode, Internal pull up, PDT True clock output.
	Q13+	Output	Diff.	-
22	Q13-	Output	Diff.	Complementary clock output.
23	Q12+	Output	Diff.	True clock output.
24 25	Q12- OE12#	Output Input	CMOS	Complementary clock output. Active low input for enabling output 12. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
26	Q11+	Output	Diff.	True clock output.
27	Q11-	Output	Diff.	Complementary clock output.
28	OE11#	Input	CMOS	Active low input for enabling output 11. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
29	Q10+	Output	Diff.	True clock output.
30	Q10-	Output	Diff.	Complementary clock output.
31	OE10#	Input	CMOS	Active low input for enabling output 10. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.





Pin Number	Pin Name	Ту	pe	Description
				SBI_EN = 0: OE mode
				0 = Enable output 9, 1 = Disable output 9
32	OE9#_SBI_IN	Input	CMOS	SBI_EN = 1: SBI mode
				This pin becomes SBI_IN pin.
				For both OE mode and SBI mode, Internal pull up, PDT.
33	VDDCLK	Power		Clock Power supply.
34	Q9+	Output	Diff.	True clock output.
35	Q9-	Output	Diff.	Complementary clock output.
36	OE8#	Input	CMOS	Active low input for enabling output 8. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
37	Q8+	Output	Diff.	True clock output.
38	Q8-	Output	Diff.	Complementary clock output.
39	OE7#	Input	CMOS	Active low input for enabling output 7. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
40	Q7+	Output	Diff.	True clock output.
41	Q7-	Output	Diff.	Complementary clock output.
42	Q6+	Output	Diff.	True clock output.
43	Q6-	Output	Diff.	Complementary clock output.
44	VDDCLK	Power		Clock Power supply.
45	OE6#	Input	CMOS	Active low input for enabling output 6. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
46	Q5+	Output	Diff.	True clock output.
47	Q5-	Output	Diff.	Complementary clock output.
				SBI_EN = 0: OE mode
				0 = Enable output 5, $1 =$ Disable output 5
48	OE5#_SBI_CLK	Input	CMOS	SBI_EN = 1: SBI mode
				This pin becomes SBI_CLK pin.
				For both OE mode and SBI mode, Internal pull up, PDT.
49	Q4+	Output	Diff.	True clock output.
50	Q4-	Output	Diff.	Complementary clock output.
51	OE4#	Input	CMOS	Active low input for enabling output 4 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
52	Q3+	Output	Diff.	True clock output.
53	Q3-	Output	Diff.	Complementary clock output.
54	OE3#	Input	CMOS	Active low input for enabling output 3. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.





Pin Number	Pin Name	Ту	pe	Description
				SBI_EN = 0: OE mode
				0 = Enable output 2, 1 = Disable output 2
55	OE2#_SBI_OUT	I/O	CMOS	SBI_EN = 1: SBI mode
				This pin becomes SBI_OUT pin.
				For both OE mode and SBI mode, Internal pull up, PDT.
56	Q2+	Output	Diff.	True clock output.
57	Q2-	Output	Diff.	Complementary clock output.
58	VDDCLK	Power		Clock Power supply.
59	Q1+	Output	Diff.	True clock output.
60	Q1-	Output	Diff.	Complementary clock output.
61	OE1#	Input	CMOS	Active low input for enabling output 1. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
62	Q0+	Output	Diff.	True clock output.
63	Q0-	Output	Diff.	Complementary clock output.
64	OE0#	Input	CMOS	Active low input for enabling output 0. 0 = Enable output, 1 = Disable output. Internal pull up, PDT.
EPAD	GND	Power		Ground pin.



Note:



### **Maximum Ratings**

(Above which useful life may be impaired. For user guidelines, not tested.) Storage Temperature......-65°C to +150°C Supply Voltage to Ground Potential, VDDxx..... -0.5V to 3.9V Input Voltage .....-0.5V to V<sub>DD</sub>+0.3V, not exceed 3.9V Input Voltage (PDT Pin) ..... -0.5V to 3.9V ESD Protection (HBM) ...... 2000V 

Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

### **Operating Conditions**

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>DDDIG</sub> , V <sub>DDCLK</sub>	Power Supply Voltage		2.97	3.3	3.63	V
I <sub>DD</sub>	Power Supply Current	$V_{DDDIG}$ + $V_{DDCLK}$ , All outputs active @100MHz		165	200	mA
I <sub>DD_PD</sub>	Power Supply Power Down <sup>(1)</sup> Current	V <sub>DDDIG</sub> + V <sub>DDCLK</sub> , All outputs LOW/LOW		6	7.5	mA
I <sub>DDVDDCLK_PD</sub>	Power Supply Current Power Down(1) for Outputs	V <sub>DDCLK</sub> , All outputs LOW/LOW		0.65	1.21	mA
T <sub>A</sub>	Ambient Temperature	Industrial grade	-40		105	°C

Note:

1. Input clock is not running.

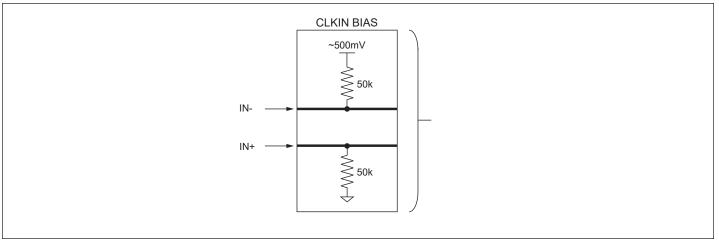
2. Outputs drive 10 inch trace.

# **Input Electrical Characteristics**

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
R <sub>pu</sub>	Internal Pull up Resistance			120		ΚΩ
R <sub>dn</sub>	Internal Pull down Resistance			120		ΚΩ
L <sub>PIN</sub>	Pin Inductance				7	nH







#### Figure 1. Input Clock Bias Network

### **SMBus Electrical Characteristics**

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>DDSMB</sub>	Nominal Bus Voltage		2.7		3.6	V
		SMBus, V <sub>DDSMB</sub> = 3.3V	2.1		3.6	
V <sub>IHSMB</sub>	SMBus Input High Voltage	SMBus, V <sub>DDSMB</sub> < 3.3V	0.65 V <sub>DDSMB</sub>			V
<b>X</b> 7		SMBus, V <sub>DDSMB</sub> = 3.3V			0.8	3.7
V <sub>ILSMB</sub>	SMBus Input Low Voltage	SMBus, V <sub>DDSMB</sub> < 3.3V			0.8	V
I <sub>SMBSINK</sub>	SMBus Sink Current	SMBus, at V <sub>OLSMB</sub>	4			mA
VOLSMB	SMBus Output Low Voltage	SMBus, at I <sub>SMBSINK</sub>			0.4	V
f <sub>MAXSMB</sub>	SMBus Operating Frequency	Maximum frequency			400	kHz
t <sub>RMSB</sub>	SMBus Rise Time	(Max V <sub>IL</sub> - 0.15) to (Min V <sub>IH</sub> + 0.15)			300	ns
t <sub>FMSB</sub>	SMBus Fall Time	(Min $\rm V_{IH}$ + 0.15) to (Max $\rm V_{IL}$ - 0.15)			300	ns

### **Side-Band Interface Electrical Characteristics**

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
t <sub>PERIOD</sub>	Clock Period	Clock period.	40			ns
tSETUP	SHFT Setup Time to Clock	SHFT_LDB high to SBI_CLK rising edge.	10			ns
t <sub>DSU</sub>	SBI_IN Setup Time	SBI_IN setup to SBI_CLK rising edge.	5			ns





Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
t <sub>DHOLD</sub>	SBI_IN Hold Time	SBI_IN hold after SBI_CLK ris- ing edge.	2			ns
t <sub>CO</sub>	SBI_CLK to SBI_OUT	SBI_CLK rising edge to SBI_ OUT valid.	2			ns
t <sub>SHOLD</sub>	SHFT Hold Time	SHFT_LDB hold (high) after SBI_CLK rising edge (SBI_CLK to SHFT_LDB falling edge).	10			ns
t <sub>en/dis</sub>	Enable/Disable Time	Delay from SHFT_LDB falling edge to next output configuration taking effect.	4		12	clocks
t <sub>SLEW</sub>	Slew Rate	SBI_CLK (between 20% and 80%).	0.7		4	V/ns
		SBI_OUT impedance		50		Ω

### **LVCMOS DC Electrical Characteristics**

Temperature =  $T_A$ : Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>IH</sub>	Input High Voltage	Single-ended inputs, except SMBus	0.75 VDD		VDD +0.3	V
V <sub>IM</sub>	Input Mid Voltage	SADR0_TRI, SADR1_TRI, BW_ SEL_TRI	0.4VDD	0.5VDD	0.6VDD	V
V <sub>IL</sub>	Input Low Voltage	Single-ended inputs, except SMBus	-0.3		0.25 VDD	V
I <sub>IH</sub>	Input High Current	Single-ended inputs with pullup/ pulldown resistor, V <sub>IN</sub> = V <sub>DD</sub>			50	uA
I <sub>IL</sub>	Input Low Current	Single-ended inputs with pullup/ pulldown resistor, V <sub>IN</sub> = 0V	-50			μΑ
C <sub>IN</sub>	Input Capacitance		1.5		5	pF

# HCSL Input Characteristics<sup>(1)</sup>

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
	Input Frequency	$V_{DD} = 3.3 V$	1	100	400	MHz
f <sub>IN</sub>	Autoparking on		25			MHz
	Autoparking off		1			MHz
V <sub>IHDIF</sub>	Diff. Input High Voltage <sup>(3)</sup>	IN+, IN-, single-end measure- ment	330		1150	mV





Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>ILDIF</sub>	Diff. Input Low Voltage <sup>(3)</sup>	IN+, IN-, single-end measure- ment	-300	0	300	mV
V <sub>SWING</sub>	Diff. Input Swing Voltage	Peak to peak value (V <sub>IHDIF</sub> - V <sub>ILDIF</sub> )	200			mV
V <sub>COM</sub>	Common mode voltage		100		1200	mV
t <sub>RF</sub>	Diff. Input Slew Rate <sup>(2)</sup>		0.7			V/ns
I <sub>IN</sub>	Diff. Input Leakage Current	$V_{IN+} = V_{DD}, V_{IN-} = 0.8V$	-40		100	uA
t <sub>DC</sub>	Diff. Input Duty Cycle	Measured differentially	45		55	%
tj <sub>c-c</sub>	Diff. Input Cycle to cycle jitter	Measured differentially			125	ps

Note:

1. Guaranteed by design and characterization, not 100% tested in production

2. Slew rate measured through +/-75mV window centered around differential zero

The device can be driven by a single-ended clock by driving the true clock and biasing the complement clock input to the Vbias, where Vbias is (VIH-VIL)/2 3.

### **HCSL Output Characteristics**

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
V <sub>OH</sub>	Output voltage high		660	780	900	mV
V <sub>OL</sub>	Output voltage low		-150	20	150	mV
Vcross absolute	Absolute Crossing point Voltage		250		550	mV
V <sub>cross_var</sub>	Crossing point voltage variation				140	mV
f <sub>OUT</sub>	Output Frequency			100	400	MHz
t <sub>RF</sub>	Slew rate <sup>(1,2,3)</sup>	Scope averaging on, 10 inch trace	1.5	3.0	4	V/ns
Dt <sub>RF</sub>	Slew rate matching <sup>(1,2,4)</sup>	Scope averaging on, 10 inch trace			20	%
t <sub>SKEW</sub>	Output Skew <sup>(1,2)</sup>	Averaging on, $V_T = 50\%$			50	ps
t <sub>DC</sub>	Diff. Output Duty Cycle	Measured differentially	45		55	%
T <sub>pd</sub>	Propagation Delay			2.0	3	ns
t <sub>OELAT</sub>	Output Enable Latency	Q start after OE# assertion Q stop after OE# deassertion	4	5	10	clocks
t <sub>PDLAT</sub>	PD# De-assertion	Differential outputs enable after PD# de-assertion		20	300	μs
t <sub>LOSAssert</sub>	LOS Assert Time	Time from disappearance of input clock to LOS assert		50	100	ns





Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
t <sub>LOSDeassert</sub>	LOS De-assert Time	Time from appearance of input clock to LOS de-assert		6	9	clocks

Note:

1. Guaranteed by design and characterization, not 100% tested in production

2. Measured from differential waveform

Slew rate is measured through the Vswing voltage range centered around differential 0V, within +/-150mV window 3.

Slew rate matching is measured through +/-75mV window centered around differential zero 4.

5. Duty cycle distortion is the difference in duty cycle between the out and input clock

### **HCSL Output AC Characteristics - Phase Jitter**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Тур.	Max.	Specification Limit	Units
t <sub>jphPCIeG1-CC</sub>		PCIe Gen1 (2.5 GT/s)	1300		86,000	fs p-p
1		PCIe Gen2 Hi Band (5.0 GT/s)	4		3,100	
tjphPCIeG2-CC	Additive PCIe Phase litter	PCIe Gen2 Lo Band (5.0 GT/s)	58		3,000	
t <sub>jphPCIeG3-CC</sub>	(Common Clocked Architec-	PCIe Gen3 (8.0 GT/s)	19		1,000	( DMC
t <sub>jphPCIeG4-CC</sub>	ture) SSC $\leq$ -0.5%	PCIe Gen4 (16.0 GT/s)	19		500	fs RMS
t <sub>jphPCIeG5-CC</sub>		PCIe Gen5 (32.0 GT/s)	5	7.5	150	
t <sub>jphPCIeG6-CC</sub>		PCIe Gen6 (64.0 GT/s)	3	5.8	100	
t <sub>jphPCIeG1-IR</sub>		PCIe Gen1 (2.5 GT/s)	111			
t <sub>jphPCIeG2-IR</sub>		PCIe Gen2 (5.0 GT/s)	51			
t <sub>jphPCIeG3-IR</sub>	Additive PCIe Phase Jitter (IR	PCIe Gen3 (8.0 GT/s)	23			
t <sub>jphPCIeG4-IR</sub>	Architectures - SRIS, SRNS) SSC ≤ -0.3%	PCIe Gen4 (16.0 GT/s)	22			fs RMS
t <sub>jphPCIeG5-IR</sub>		PCIe Gen5 (32.0 GT/s)	6	8.1		
t <sub>jphPCIeG6-IR</sub>		PCIe Gen6 (64.0 GT/s)	4	7		

Note: The Refclk jitter is measured after applying the filter functions found in the PCI Express Base Specification 6.0, Revision 1.0. For the exact measurements





### **SMBus Serial Data Interface**

The PI6CB332016A is a slave only device that supports block and byte protocol using a single 7-bit address and read/write bit as shown below. The highest bit of register address is to distinguish block write/read and byte write/read. when the highest bit is "1", it's the byte operation, the highest bit is "0", it's the block operation.

Read and write block transfers can be stopped after any complete byte transfer.

#### **Address Assignment**

A6	A5	A4	A3	A2	A1	A0	R/W
1	1	0	S	1/0			

Note: SMBus address is latched on SADR pin

#### **Byte Write**

1 b	it	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit	1 bit
Start	bit	Address	W(0)	Ack	Beginning Byte location=N	Ack	data	Ack	Stop bit

### **Byte Read**

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	1 bit	7 bits	1 bit	8 bits	1 bit	1 bit
Start bit	Address	W(0)	Ack	Beginning Byte location=N	Ack	Repeat Start bit	Address	R(1)	data	NAck	Stop bit

### **Block Write**

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	1 bit
Start bit	Address	W(0)	Ack	Beginning Byte Location = N	Ack	Data Byte count = X	Ack	Beginning Date Byte (N)	Ack	 Data Byte (N+X-1)	Ack	Stop bit

#### **Block Read**

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit
Start bit	Address	W(0)	Ack	Beginning Byte Location = N	Ack	Repeat Start bit	Address	R(1)	Ack	Data By count =	ACK	Beginnin Date Byt (N)	0
											8 bits	1 bit	1 bit
										Data Byte (N+X-1)	NAck	Stop bit	





Address	Selection				Bin	ary Value				
SADR_tril SADR_tr		7	6	5	4	3	2	1	Read/Write	Hex Value
	0	1	1	0	1	1	0	0	0	D8
0	М	1	1	0	1	1	0	1	0	DA
	1	1	1	0	1	1	1	1	0	DE
	0	1	1	0	0	0	0	1	0	C2
М	М	1	1	0	0	0	1	0	0	C4
	1	1	1	0	0	0	1	1	0	C6
	0	1	1	0	0	1	0	1	0	CA
1	М	1	1	0	0	1	1	0	0	CC
	1	1	1	0	0	1	1	1	0	CE

### **SMBus Address Decode**





### **Side-Band Interface**

This interface consists of DATA, CLK and SHFT\_LD# pins. When the SHFT\_LD# pin is high, the rising edge of CLK can shift DATA into the shift register. After shifting data, the falling edge of SHFT\_LD# clocks the shift register contents to the Output register.

When the SBI is enabled, DATA, CLK, and SHFT\_LD# are enabled on OE9#, OE5# and OE13# respectively. Additionally, SMBus registers for masking off the disable function of the shift register (0 value of a bit) become active. When set to a one, the mask register forces its respective output to 'enabled.' This prevents accidentally disabling critical outputs when using the SBI.

An SMBus read back bit in Byte 4 indicates which output enable control interface is enabled.

When the SBI is enabled, and power has been applied, the SBI is active, even if the PWRGD/PWRDN# pin indicates the part is in power down. This allows loading the shift register and transferring the contents to the output register before the assertion of PWRGD. Note that the mask registers are part of the normal SMBus interface and cannot be accessed when the PWRGD/PWRDN# is low. Figure 2 provides a functional description of the SBI.

The SBI and the traditional SMBus output enable registers both default to the 'output enabled' state at power-up. The mask registers default to zero at power-up, allowing the shift bits to disable their respective output. See Figure 2.

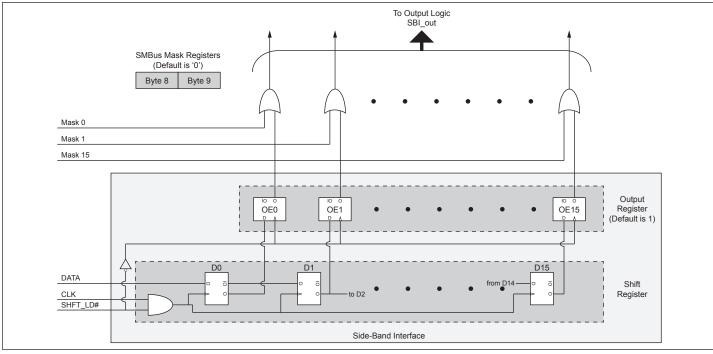
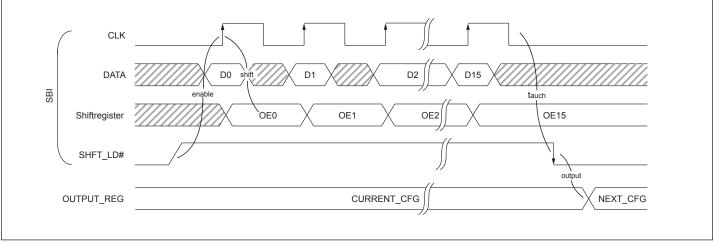


Figure 2. Side Band Interface Control Logic Description

Figures 3 shows the basic timing of the side-band interface. The SHFT\_LD# pin goes high to enable the CLK input. Next, the rising edge of CLK clocks enable DATA into the shift register. After the 16th clock for output 16, stop the clock low and drive the SHFT\_LD# pin low. The falling edge of SHFT\_LD# clocks the shift register contents to the output register, enabling or disabling the outputs. Always shift 16 bits of data into the shift register to control the outputs.







#### Figure 3. Side Band Interface Functional Timing

The SBI interface supports clock rates up to 10MHz. Multiple devices may share CLK and DATA pins. Dedicating a SHFT\_LD# pin to each devices allows its use as a chip-select pin. When the SHFT\_LD# pin is low, the PI6CB3320xx ignores any activity on the CLK and DATA pins.





### **SMBus Registers**

#### Byte 0: OUTPUT\_ENABLE\_0

Bit	<b>Control Function</b>	Description	Туре	Power Up Condition	Definition
7	Q7_En	Output Enable for Q7	RW	1	
6	Q6_En	Output Enable for Q6	RW	1	
5	Q5_En	Output Enable for Q5	RW	1	
4	Q4_En	Output Enable for Q4	RW	1	0 = output is disabled
3	Q3_En	Output Enable for Q3	RW	1	1 = output is enabled
2	Q2_En	Output Enable for Q2	RW	1	-
1	Q1_En	Output Enable for Q1	RW	1	
0	Q0_En	Output Enable for Q0	RW	1	

#### Byte 1: OUTPUT\_ENABLE\_1

-					
Bit	Control Function	Description	Туре	Power Up Condition	Definition
7	Q15_EN	Output Enable for Q15	RW	1	
6	Q14_EN	Output Enable for Q14	RW	1	
5	Q13_EN	Output Enable for Q13	RW	1	
4	Q12_EN	Output Enable for Q12	RW	1	0 = output is disabled (low)
3	Q11_EN	Output Enable for Q11	RW	1	1 = output is enabled
2	Q10_EN	Output Enable for Q10	RW	1	
1	Q9_EN	Output Enable for Q9	RW	1	
0	Q8_EN	Output Enable for Q8	RW	1	

#### Byte 2: OE\_PIN\_READBACK\_0

Bit	Control Function	Description	Туре	Power Up Condition	Definition
7	RB_OE#_7	Status of OE#7	RO	Pin	
6	RB_OE#_6	Status of OE#6	RO	Pin	
5	RB_OE#_5	Status of OE#5	RO	Pin	
4	RB_OE#_4	Status of OE#4	RO	Pin	0 = OE# pin low
3	RB_OE#_3	Status of OE#3	RO	Pin	1 = OE# pin high
2	RB_OE#_2	Status of OE#2	RO	Pin	
1	RB_OE#_1	Status of OE#1	RO	Pin	
0	RB_OE#_0	Status of OE#0	RO	Pin	





0 = pin low

1 = pin high

### PI6CB332016A

Byte 3: OE_PIN_READBACK_1							
Bit	Control Function	Description	Туре	Power Up Condition	Definition		
7	RB_OE#_15	Status of OE#15	RO	Pin			
6	RB_OE#_14	Status of OE#14	RO	Pin			
5	RB_OE#_13	Status of OE#13	RO	Pin			
4	RB_OE#_12	Status of OE#12	RO	Pin	0 = OE# pin low		
3	RB_OE#_11	Status of OE#11	RO	Pin	1 = OE# pin high		
2	RB_OE#_10	Status of OE#10	RO	Pin			
1	RB_OE#_9	Status of OE#9	RO	Pin			
0	RB_OE#_8	Status of OE#8	RO	Pin			
Byte 4:	SBEN_RDBK_ ACP_	CONFIG					
Bit	Control Function	Description	Туре	Power Up Condition	Definition		
7			RW	1			
6	Reserved		RW	1			
5			RW	1			
4	ACP_ENABLE	Enable Automatic Clock Parking to low/low when LOS event is detected	RW	1	0 = disable ACP 1 = enable ACP		
3			RW	1			
2	Reserved		RW	1			
1			RW	0			

### Byte 5: VENDOR\_REVISION\_ID

Status of SBI\_ENQ

RB\_SBI\_ENQ

0

Bit	Control Function	Description	Туре	Power Up Condition	Definition
7			RO		
6	- RID		RO		
5		REVISION ID, A rev is 0000	RO	0000	
4			RO		
3			RO		
2	VID	VENDOR ID, Diodes	RO	- 0011 -	
1			RO		
0			RO		

RO

Pin





Byte 6	Byte 6: DEVICE_ID						
Bit	Control Function	Description	Туре	Power Up Condition	Definition		
7			RO				
6			RO				
5	DEVICE_ID		RO				
4			RO	PI6CB332016A			
3		Device ID	RO	(85Ω) 0H50			
2			RO				
1			RO				
0			RO				

#### Byte 7: BYTE\_COUNT

Bit	Control Function	Description	Туре	Power Up Condition	Definition
7			RW	0	
6	Reserved		RW	0	
5			RW	0	
4			RW		
3			RW		
2	BC	Writing to this register configures how many bytes will be read back in a block read.	RW	0x7	
1		by tes will be read back in a block read.	RW		
0			RW		

#### Byte 8: SBI MASK 0

Bit	Control Function	Description	Туре	Power Up Condition	Definition		
7	MASK7	Masks off Side-band Disable for Q7	RW	0			
6	MASK6	Masks off Side-band Disable for Q6	RW	0			
5	MASK5	Masks off Side-band Disable for Q5	RW	0			
4	MASK4	Masks off Side-band Disable for Q4	RW	0	0 = SBI may disable the output		
3	MASK3	Masks off Side-band Disable for Q3	RW	0	1 = SBI cannot disable the output		
2	MASK2	Masks off Side-band Disable for Q2	RW	0	output		
1	MASK1	Masks off Side-band Disable for Q1	RW	0			
0	MASK0	Masks off Side-band Disable for Q0	RW	0			





Bit	Control Function	Description	Туре	Power Up Condition	Definition
7	MASK15	Masks off Side-band Disable for Q15	RW	0	
6	MASK14	Masks off Side-band Disable for Q14	RW	0	
5	MASK13	Masks off Side-band Disable for Q13	RW	0	
4	MASK12	Masks off Side-band Disable for Q12	RW	0	0 = SBI may disable the output
3	MASK11	Masks off Side-band Disable for Q11	RW	0	1 = SBI cannot disable the output
2	MASK10	Masks off Side-band Disable for Q10	RW	0	Jourpur
1	MASK9	Masks off Side-band Disable for Q9	RW	0	
0	MASK8	Masks off Side-band Disable for Q8	RW	0	
Byte 1	10: RESERVED				
Byte	11: SBI_READBACK_0	<b>)</b> <sup>(1)</sup>			
Bit	<b>Control Function</b>	Description	Туре	Power Up Condition	Definition
7	SBI_Q7	Readback of Side-band Disable for Q7	RO	Х	
6	SBI_Q6	Readback of Side-band Disable for Q6	RO	Х	
5	SBI_Q5	Readback of Side-band Disable for Q5	RO	Х	
4	SBI_Q4	Readback of Side-band Disable for Q4	RO	Х	0 = bit low
3	SBI_Q3	Readback of Side-band Disable for Q3	RO	Х	1 = bit high
2	SBI_Q2	Readback of Side-band Disable for Q2	RO	Х	
1	SBI_Q1	Readback of Side-band Disable for Q1	RO	Х	
0	SBI_Q0	Readback of Side-band Disable for Q0	RO	Х	
Byte 1	12: SBI_READBACK_	1(1)			·
Bit	Control Function	Description	Туре	Power Up Condition	Definition
7	SBI_Q15	Readback of Side-band Disable for Q15	RO	Х	
6	SBI_Q14	Readback of Side-band Disable for Q14	RO	Х	]
5	SBI_Q13	Readback of Side-band Disable for Q13	RO	Х	
4	SBI_Q12	Readback of Side-band Disable for Q12	RO	Х	0 = bit low
3	SBI_Q11	Readback of Side-band Disable for Q11	RO	Х	1 = bit high
2	SBI_Q10	Readback of Side-band Disable for Q10	RO	Х	]
1	SBI_Q9	Readback of Side-band Disable for Q9	RO	Х	]
	SBI_Q8	Readback of Side-band Disable for Q8	RO	Х	]





Bit	Control Function	Description	Туре	Power Up Condition	Definition
7			RW		
6		Global Differential output Control	RW	07	
5	AMP	0.625V~1V 25mV/step Default = 0.8V	RW	0x/	
4			RW		
3			RW		
2			RW	Ox0 Ox0 Power Up Condition	
1	Reserved		RW		
0			RW		
Byte 1	8: POWERDOWN_R	ESTORE_LOS#	·		
Bit	Control Function	Description	Туре	Power Up Condition	Definition
7		Enable receiver bies when IN is AC sounded	RW	0	0 = DC coupled input
/	AC_IN	Enable receiver bias when IN is AC coupled	KVV	0	1 = AC coupled input
6	Rx_TERM	Enable termination resistors on IN	RW	0	0 = input termination R is disabled 1 = input termination R is
				Power Up Condition 0	enabled
5	Reserved		RW	0	
4	Reserved		RW	0	
					0 = Config Cleared
3	PD_RESTORE#	Save Configuration in Power Down	RW	1	1 = Config Saved
	Reserved		RW	1	
2			RW	0	
2	Reserved				





				Power Up	
Bit	Control Function	Description	Туре	Condition	Definition
7	Q7_SLEWRATE	Q7 Slewrate Control	RW	pin status	_
6	Q6_SLEWRATE	Q6 Slewrate Control	RW	pin status	
5	Q5_SLEWRATE	Q5 Slewrate Control	RW	pin status	
4	Q4_SLEWRATE	Q4 Slewrate Control	RW	pin status	0 = low slew rate
3	Q3_SLEWRATE	Q3 Slewrate Control	RW	pin status	1 = high slew rate
2	Q2_SLEWRATE	Q2 Slewrate Control	RW	pin status	
1	Q1_SLEWRATE	Q1 Slewrate Control	RW	pin status	
0	Q0_SLEWRATE	Q0 Slewrate Control	RW	pin status	
Byte 2	1: Output_Slew_Rate_	_1			
Bit	Control Function	Description	Туре	Power Up Condition	Definition
7	Q15_SLEWRATE	Q15 Slewrate Control	RW	pin status	
6	Q14_SLEWRATE	Q14 Slewrate Control	RW	pin status	
5	Q13_SLEWRATE	Q13 Slewrate Control	RW	pin status	
4	Q12_SLEWRATE	Q12 Slewrate Control	RW	pin status	0 = low slew rate
3	Q11_SLEWRATE	Q11 Slewrate Control	RW	pin status	1 = high slew rate
2	Q10_SLEWRATE	Q10 Slewrate Control	RW	pin status	
1	Q9_SLEWRATE	Q9 Slewrate Control	RW	pin status	
0	Q8_SLEWRATE	Q8 Slewrate Control	RW	pin status	
Byte 2	2-37: RESERVED (De	fault: 0xXX)			
Byte 3	8: WRITE_LOCK_N	OCLEAR			
Bit	Control Function	Description	Туре	Power Up Condition	Definition
7			RW		
6			RW		
5			RW		
4	Reserved		RW	1'b0000000	
3			RW	]	
2			RW		
1			RW		
0	WRITE_LOCK	Non-clearable SMBus Write Lock bit. When written to one, the SMBus control registers can- not be written to. This bit can only be cleared by	RW	0	0 = SMBus not locked for writ- ing by this bit. See WRITE_ LOCK_RW1C bit.





Byte 3	9: WRITE_LOCK_CI	EAR_LOS_EVENT			
Bit	Control Function	Description	Туре	Power Up Condition	Definition
7			RW1C		
6			RW1C	- 1'b000000	
5	I		RW1C		
4	Reserved		RW1C		
3	_		RW1C		
2			RW1C		
1	LOS_EVT	LOS Event Status When high, indicates that a LOS event was detected. Can be cleared by writing a 1 to it.	RW1C	0	0 = No LOS event detected 1 = LOS event detected.
0	WRITE_LOCK_ RW1C	Clearable SMBus Write Lock bit. When written to one, the SMBus control regis- ters cannot be written to. This bit can be cleared by writing a 1 to it.	RW1C	0	0 = SMBus not locked for writ- ing by this bit. See WRITE_ LOCK bit. 1 = SMBus locked for writing



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### **Applications Information**

#### **Power Down Tolerant Pins**

Pins that are Power Down Tolerant (PDT) can be driven by voltages as high as the normal VDD of the chip, even though VDD is not present (the device is not powered). There will be no ill effects to the device and it will power up normally. This feature supports disaggregation, where the PI6CB3320xx may be on one circuit board and devices that interface with it are on other boards. These boards may power up at different times, driving pins on the PI6CB3320xx before it has received power.

#### **Flexible Startup Sequencing**

PI6CB3320xx devices support Flexible Startup Sequencing (FSS), IN+/- pins are PDT. FSS allows application of CLKIN at different times in the device/system startup sequence. FSS is an additional feature that helps the system designer manage the impact of disaggregation. Table shows the supported sequences; that is, the PI6CB3320xx devices can have CLKIN running before VDD is applied, and can have VDD applied and sit for extended periods with no input clock.

#### Loss of Signal and Automatic Clock Parking

The PI6CB3320xx buffers have a Loss of Signal (LOS) circuit to detect the presence or absence of an input clock. The LOS circuit drives the open-drain LOS# pin (the "#" suffix indicates "bar", or active-low) and sets the LOS\_EVT bit in the SMBus register space. There are two slightly different LOS# pin behaviors at power up. Figure 4 and Figure 5 show the LOS# de-assertion timing for the 4, 8, 13, 16 and 20-output buffers. CLKIN is represented differentially in Figure 4 and Figure 5.

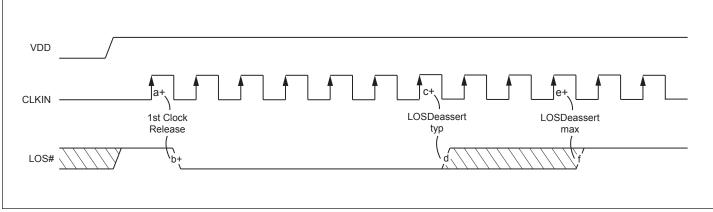
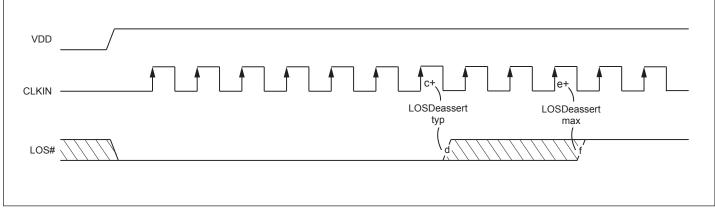
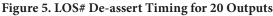


Figure 4. LOS# De-assert Timing for 4/8/13/16 Outputs

Note: The LOS circuit on the 16-output buffer requires a CLKIN edge to release the LOS# pin after power up. So, the LOS# pin will be high until the first clock edge after power up.

Figure 5 shows the LOS# de-assertion timing for the 20-output buffers. LOS# on the 20-output buffers defaults to low at power up.









The following diagram shows the LOS# assertion sequence when the CLKIN is lost. It also shows the Automatic Clock Parking (ACP) circuit bring the inputs to a Low/Low state after an LOS event. For exact timing, see Electrical Characteristics.

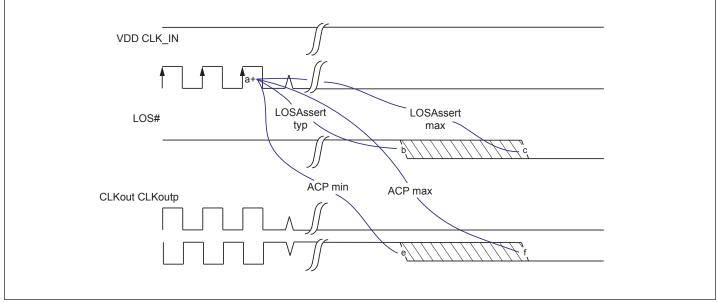
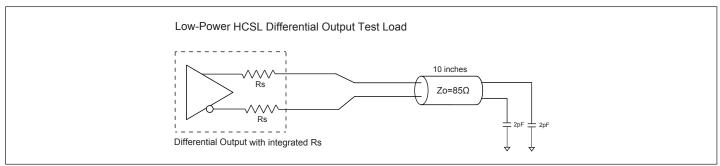


Figure 6. LOS# Assert Timing

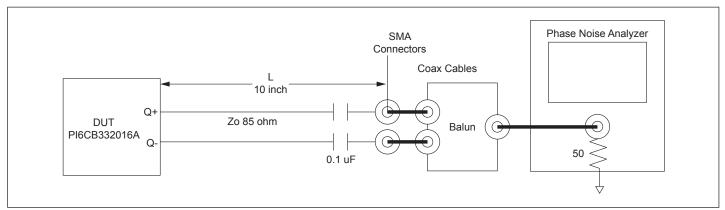




### **Test Load**



#### Figure 7. Low Power HCSL Test Circuit



### Figure 8. Test Set Up for Phase Jitter Measurement

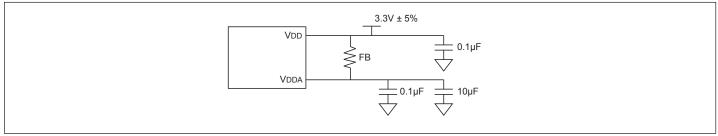
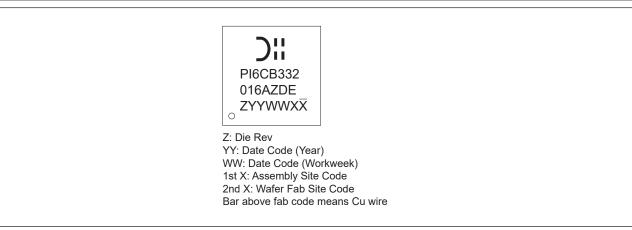


Figure 9. Power Supply Filter

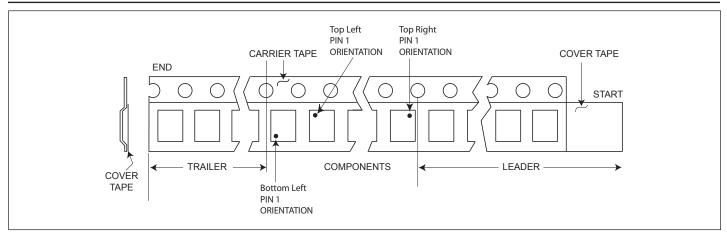




### **Part Marking**



### **Package Information**

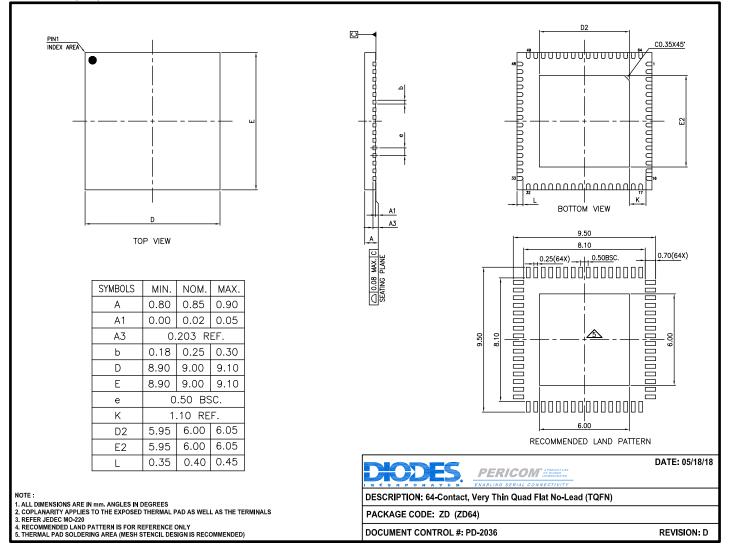






### **Packaging Mechanical**

#### 64-TQFN (ZD)



#### For latest package info.

please check: http://www.diodes.com/design/support/packaging/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/

### **Ordering Information**

Orderable Part Number	Package Code	Package Description	Pin 1 Orientation	Temperature
PI6CB332016AZDEX	ZD	64-Contact, Very Thin Quad Flat No-Lead (TQFN)	Top Right Corner	-40~105°C
PI6CB332016AZDEX-13R	ZD	64-Contact, Very Thin Quad Flat No-Lead (TQFN)	Top Left Corner	-40~105°C

#### Notes:

1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.

2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.

3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

4.  $A = For 85\Omega$  output impedance

5. E = Pb-free and Green

6. X suffix = Tape/Reel

7. For packaging detail, go to our website at: https://www.diodes.com/assets/MediaList-Attachments/Diodes-Package-Information.pdf





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